

## High Resolution Wavefront Sensor Surface Inspection

### SID4 NIR



PHASICS introduces its **high resolution wavefront sensor** for near IR region (from 1.5  $\mu\text{m}$  to 1.6  $\mu\text{m}$ ): the SID4 NIR.

For **optical metrology**, the SID4 NIR is the perfect tool to characterize IR objectives or IR lenses giving you aberrations, PSF, MTF and focal length and analyzing surface quality.

The ease of use and compactness make the SID4 NIR very simple to integrate.

#### SID4 NIR wavefront sensor key features

- High resolution (160 x 120)
- hase map interpretation modules
- P Intensity profile characterization
- Absolute measurement
- Fast measurement
- Insensitive to vibration
- Cost effective

#### SID4 NIR detailed specifications

<b>Aperture dimension</b>	3.6 x 4.8 mm <sup>2</sup>
<b>Spatial resolution</b>	29.6 $\mu\text{m}$
<b>Sampling</b>	160 x 120
<b>Wavelength range</b>	1.5 - 1.6 $\mu\text{m}$
<b>Accuracy</b>	> 15 nm RMS
<b>Sensitivity</b>	< 11 nm RMS
<b>Dynamic</b>	> 100 $\mu\text{m}$
<b>Analysis rate</b>	< 10 fps
<b>Acquisition rate</b>	60 fps
<b>Dimensions (l x H x L)</b>	44x33x57.5 mm
<b>Weight</b>	250 g



Rayscience

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